

FH3080G

N-Channel Trench Power MOSFET

Description

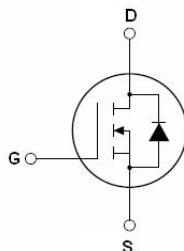
These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

General Features

- ◆ $V_{DSS}=30V$, $I_D=75A$
- ◆ $R_{DS(ON)} = 4.3m\Omega$ ($V_{GS}=10V$)
- ◆ $R_{DS(ON)} = 7.2m\Omega$ ($V_{GS}=4.5V$)
- ◆ Improved dv/dt capability
- ◆ Fast switching
- ◆ 100% EAS Guaranteed
- ◆ Green device available

Applications

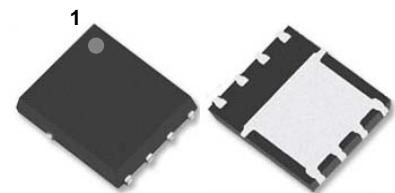
- ◆ Motor Drives
- ◆ UPS
- ◆ DC-DC Converter



Schematic diagram



Marking and pin Assignment



PDFN5X6-8L top and bottom view

Symbol	Parameter	Value	Units
V_{DS}	Drain-Source Voltage	30	V
I_D	Drain Current - Continuous ($TC= 25^\circ C$)	75	A
	- Continuous ($TC= 100^\circ C$)	47*	A
I_{DM}	Drain Current - Pulsed (Note 1)	220*	A
V_{GS}	Gate-Source Voltage	± 20	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	95	mJ
P_D	Power Dissipation ($TC = 25^\circ C$) - Derate above $25^\circ C$	46	W
T_j, T_{stg}	Operating and Storage Temperature Range	-55 to +150	°C

* Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	Value	Units
R_{eJC}	Thermal Resistance, Junction-to-Case	2.741	°C/W

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

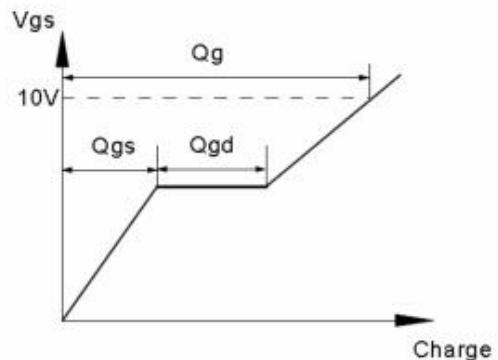
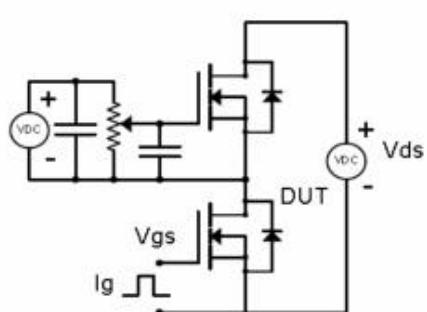
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 29.5 \text{ V}$, $V_{GS} = 0 \text{ V}$			1	μA
I_{GSSF}	Gate Leakage Current, Forward	$V_{GS} = 20 \text{ V}$, $V_{DS} = 0 \text{ V}$			100	nA
I_{GSSR}	Gate Leakage Current, Reverse	$V_{GS} = -20 \text{ V}$, $V_{DS} = 0 \text{ V}$			-100	nA
On Characteristics						
$V_{GS(TH)}$	Gate Threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	1.0	1.5	2.0	V
$R_{DS(On)}$	Drain-Source on-state resistance	$V_{GS} = 10 \text{ V}$, $I_D = 30 \text{ A}$		4.3	6.5	$\text{m}\Omega$
		$V_{GS} = 4.5 \text{ V}$, $I_D = 20 \text{ A}$		7.2	10	$\text{m}\Omega$
Dynamic Characteristics						
C_{iss}	Input capacitance	VDS=15V, VGS=0V, F=1.0Mhz		1560		pF
C_{oss}	Output capacitance			246		pF
C_{rss}	Reverse transfer capacitance			225		pF
Switching Characteristics						
$t_{d(on)}$	Turn On Delay Time	VDD=20V, ID=54A, VGS=10V, RG=4.7Ohm (Note 3, 4)		3.2		ns
t_r	Rising Time			19.6		ns
$t_{d(off)}$	Turn Off Delay Time			29.2		ns
t_f	Fall Time			18.8		ns
Q_g	Total Gate Charge	VDD=15V, ID=30A, VGS=10V (Note 3, 4)		33.7		nC
Q_{gs}	Gate-Source Charge			4.5		nC
Q_{gd}	Gate-Drain Charge			7.4		nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current			50		A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current			200		A
V_{SD}	Diode Forward Voltage	$V_{GS} = 0 \text{ V}$, $I_S = 30 \text{ A}$		1.2		V
t_{rr}	Body Diode Reverse Recovery Time	Vds=32V, Ids=20A, di/dt=100A/us		13		ns
Q_{rr}	Body Diode Reverse Recovery Charge			6		nC

Notes:

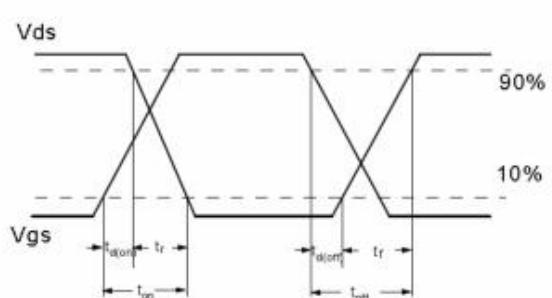
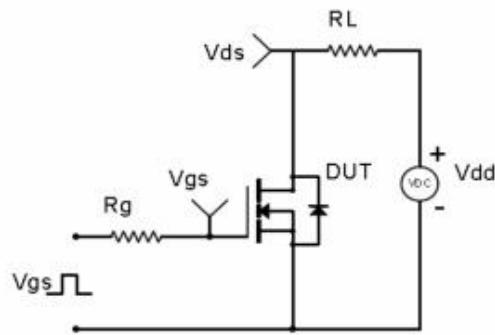
1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. L = 0.5 mH, VDD = 20V, RG = 25 Ω, Starting Tj = 25°C
3. Isd ≤ 100A, di/dt = 100A/us, VDD ≤ BVdss, Starting Tj = 25°C
4. Pulse Test : Pulse width ≤ 300us, Duty cycle ≤ 2%
5. Essentially independent of operating temperature

Test Circuit & Waveform

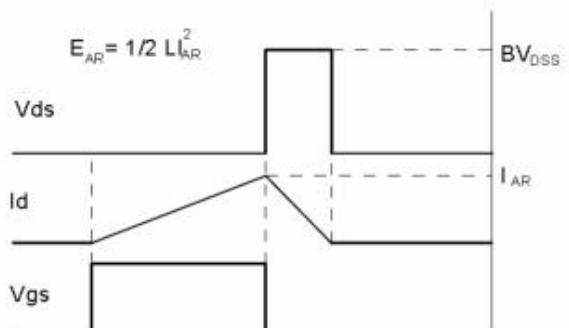
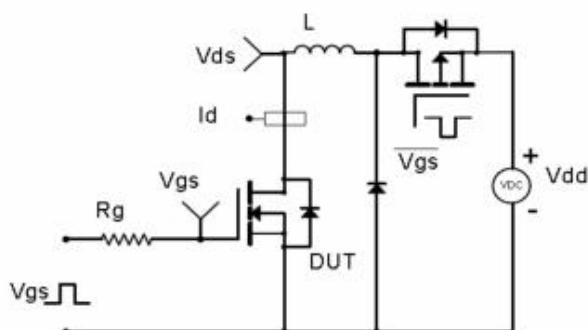
Gate Charge Test Circuit & Waveform



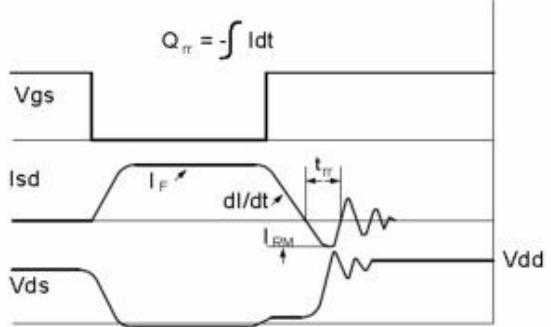
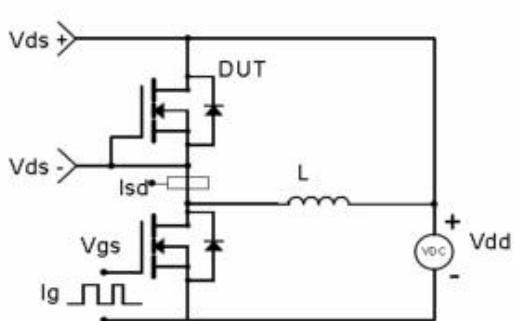
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Typical Performance Characteristics

Fig.1 Power Dissipation Derating Curve

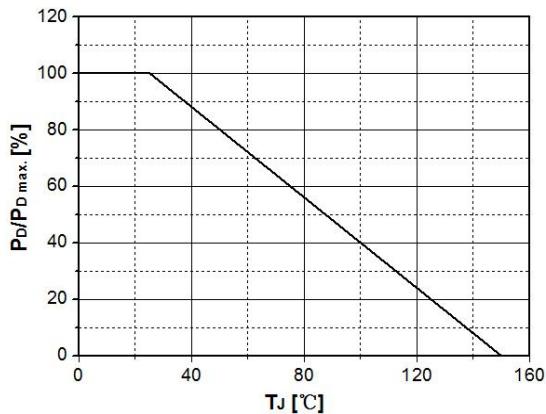


Fig.3 Typical Output Characteristics

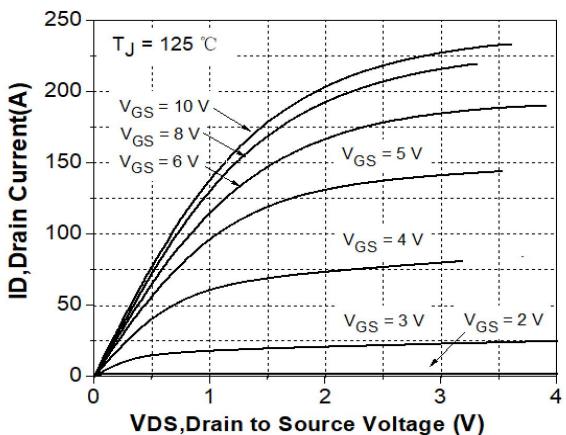


Fig.5 Typical Transfer Characteristics

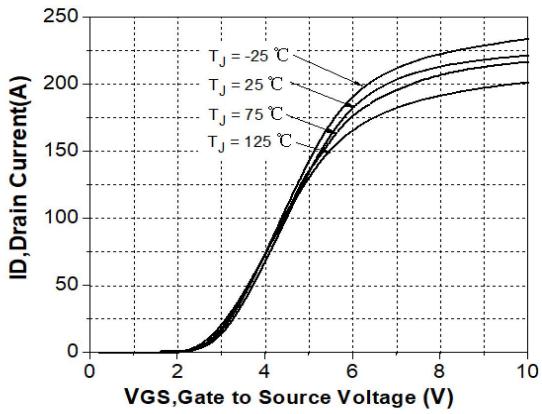


Fig.2 Avalanche Energy Derating Curve vs. Junction Temperature

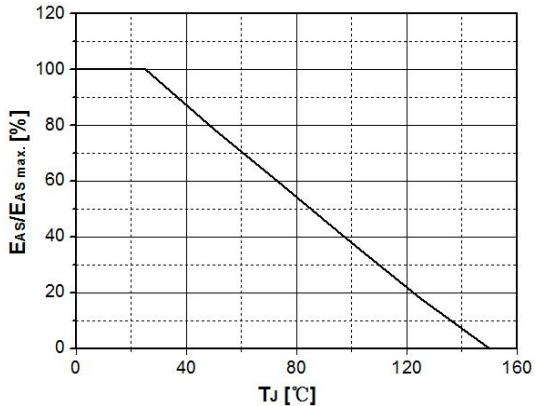


Fig.4 Transconductance vs. Drain Current

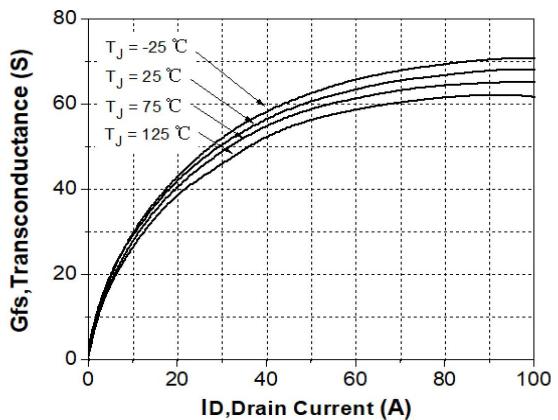


Fig.6 State Resistance vs. Drain Current @-25°C

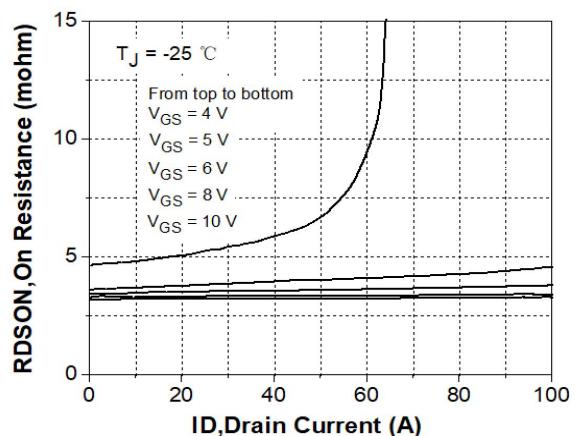


Fig.7 State Resistance vs. Drain Current @25°C

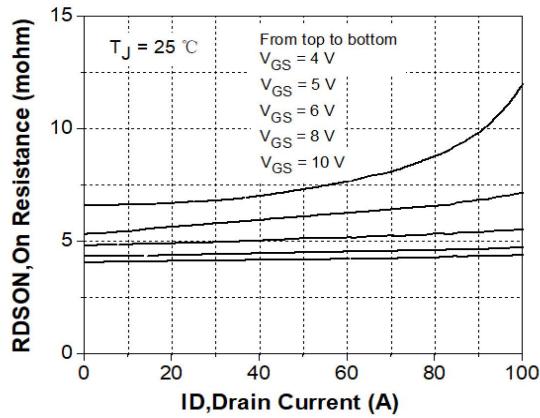


Fig.9 Typical Capacitance vs. Drain Source Voltage

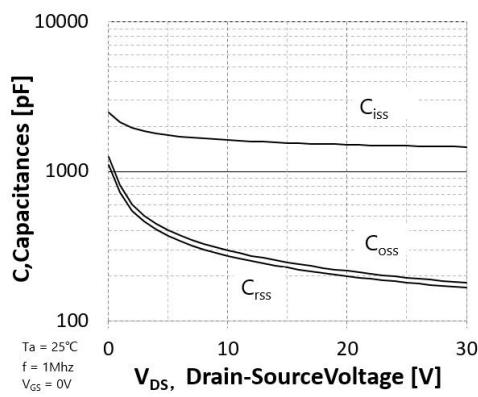


Fig.11 Breakdown Voltage vs. Junction Temperature

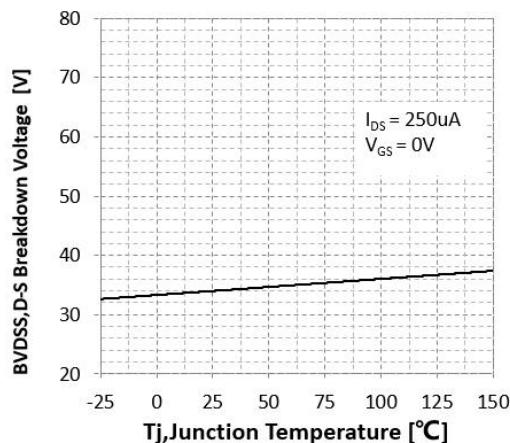


Fig. 8 State Resistance vs. Drain Current @125°C

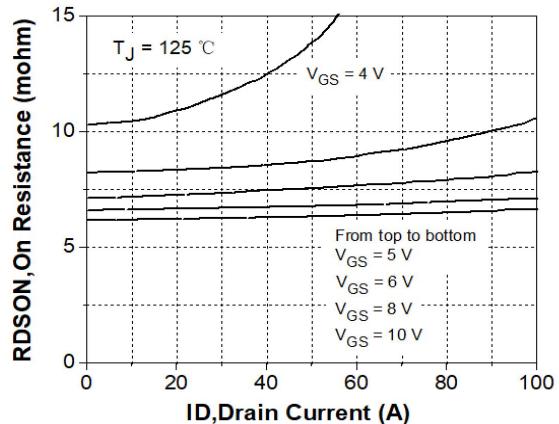


Fig.10 Dynamic Input Characteristics

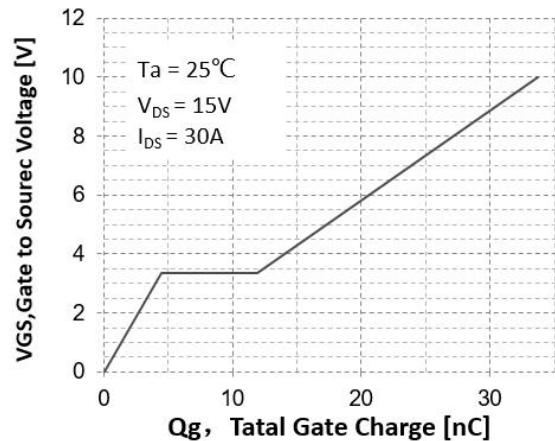


Fig. 12 Gate Threshold Voltage vs. Junction Temperature

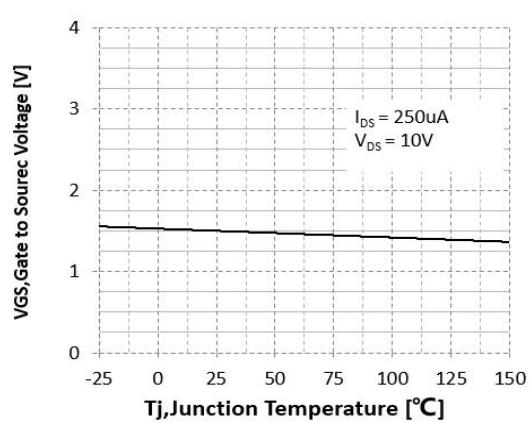


Fig.13 On-Resistance Variation vs. Junction Temperature

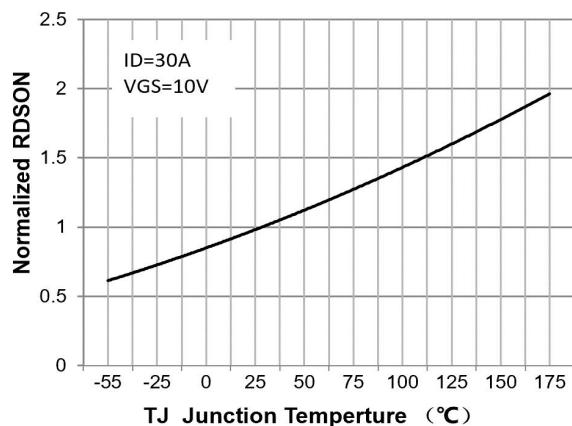


Fig.14 Maximum Drain Current vs. Case Temperature

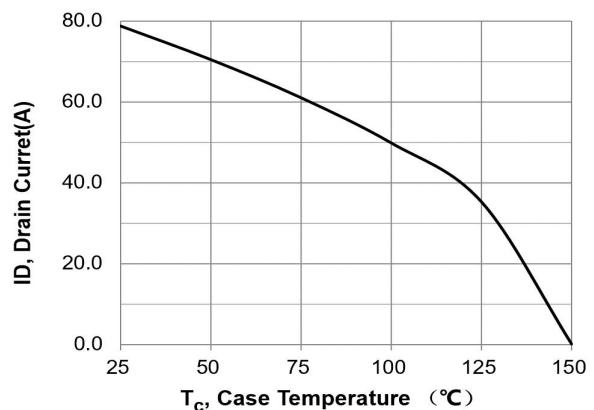


Fig.15 Body Diode Forward Voltage Vs Reverse Drain Current

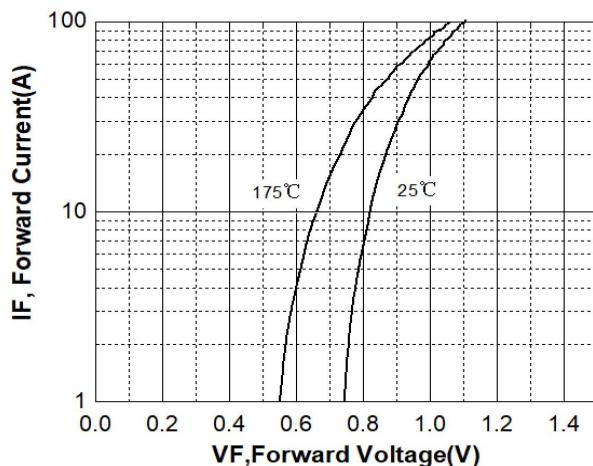


Fig.16 Safe Operating Area

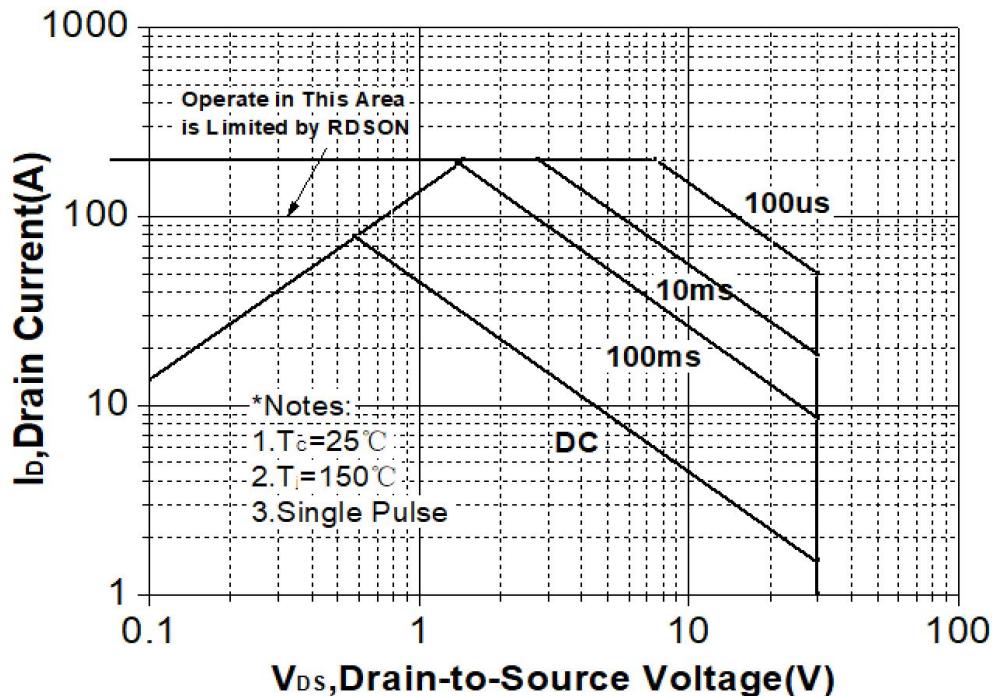
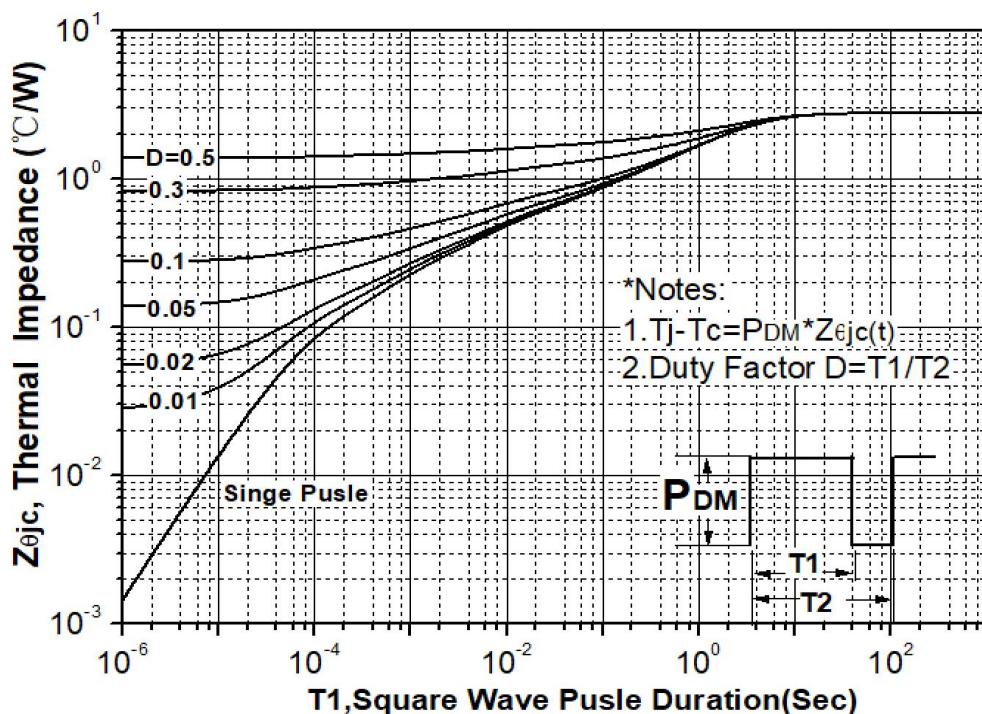
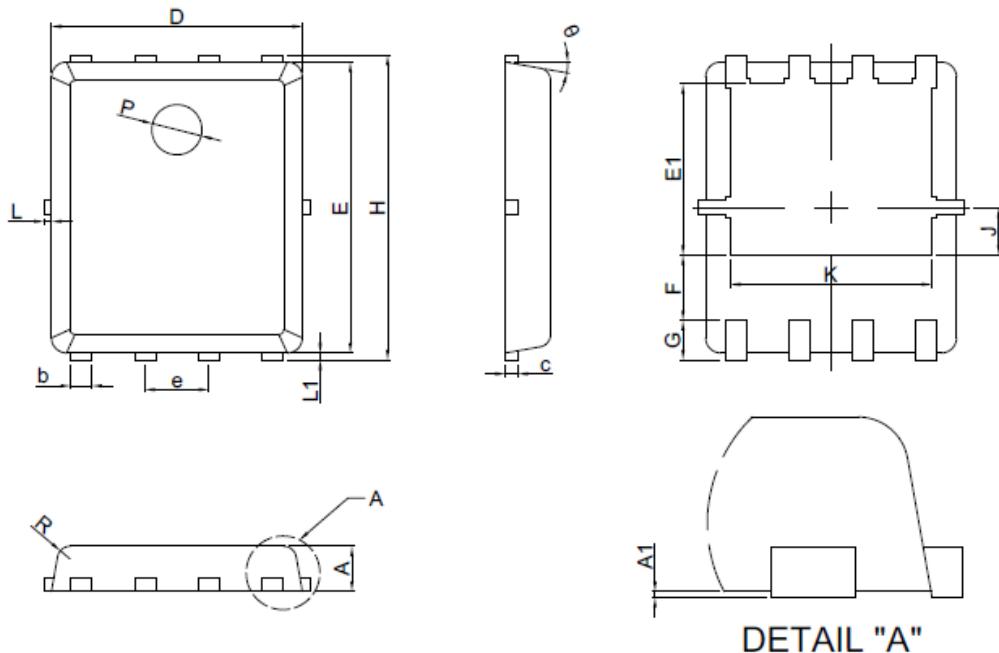


Fig. 17 Transient Thermal Response Curve



Package Information : PDFN5x6-8L



Symbol	Dimensions In Millimeters	
	MIN.	MAX.
A	0.80	1.00
A1	0.00	0.05
b	0.35	0.49
c	0.254REF	
D	4.80	5.20
F	1.40REF	
E	5.60	5.90
e	1.27BSC	
H	5.80	6.20
L1	0.10	0.18
G	0.60REF	
K	4.00REF	
L	-	0.15
J	0.95BSC	
P	1.00REF	
E1	3.40REF	
θ	6°	14°
R	0.25REF	